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PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
1G007134	12/04/2001	4271	612	2823	MALDONADO, J

**APPLICANTS: Payne Catherine; Maloney David; Lee Shihying; Lee Wai; Arkless Leslie;

** CONTINUING DATA VERIFIED:

This application is a DIV of 09/343,532 06/30/1999 PAT 6,417,112
which claims benefit of 60/092,024 07/05/1998

** FOREIGN APPLICATIONS VERIFIED:

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no		ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no		8317-123-999
Verified and Acknowledged Examiner's initials		
TITLE : Post etch cleaning composition for dual damascene system		

U.S. DEPT. OF COMM./PAT. & TM-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED
ISSUE FEE		DRAWING
Amount Due	Date Paid	
<input type="checkbox"/> TERMINAL		Application Examiner
DISCLAIMER		
PREPARED FOR ISSUE		WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368, Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.
Assistant Examiner		
Primary Examiner		

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